

Electronic Components
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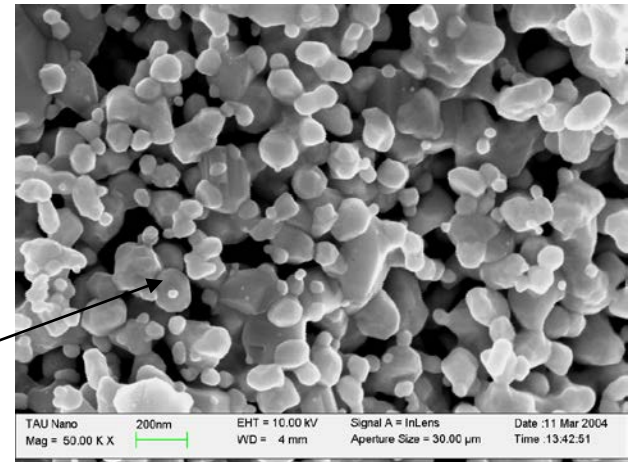
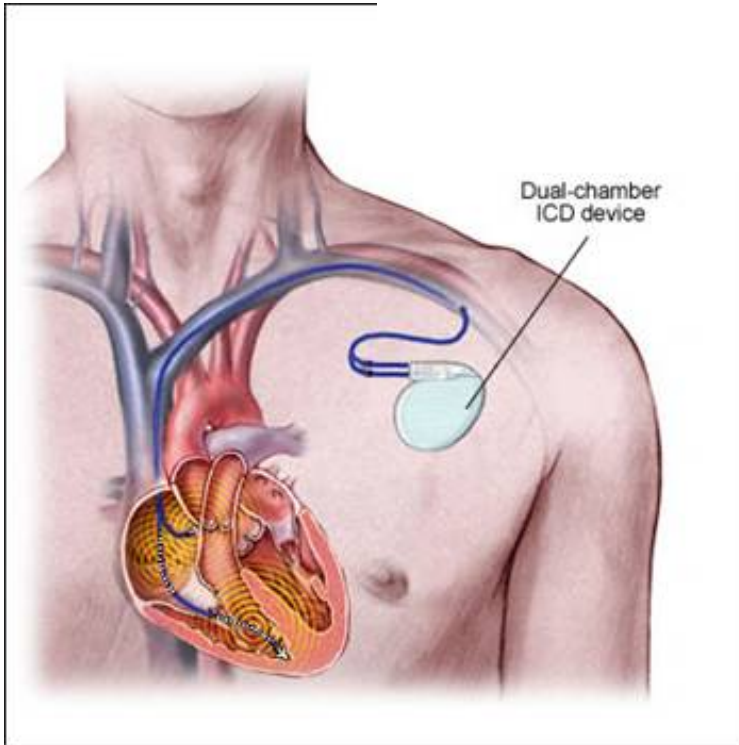
Tantalum Capacitors in Space Applications

Y. Freeman

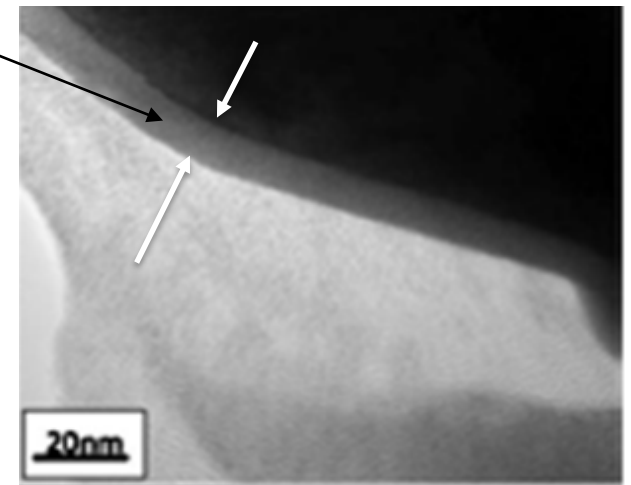
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Efficiency

Fig. 1 Medtronic cardio implant with tantalum capacitors



$$C \sim \frac{A}{d}$$

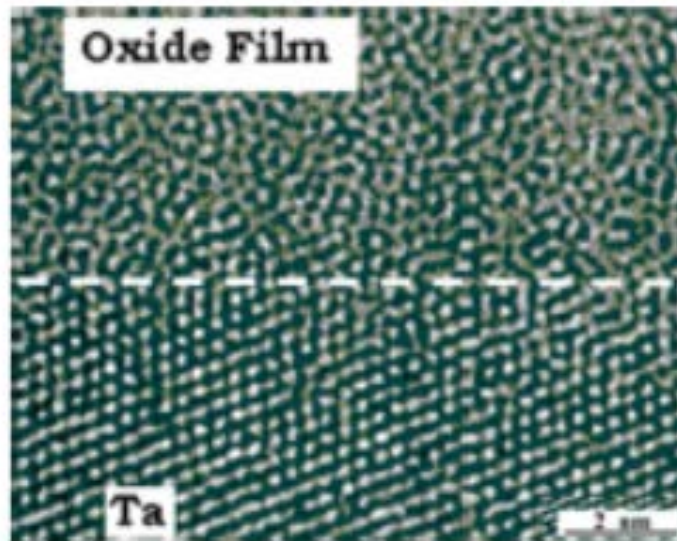


With permission from Medtronic Corporation

Charge time $\leq 8s$



Fig. 1.2 TEM image of the amorphous anodic oxide film formed on crystalline tantalum (the white spots represent individual atoms)



Entropy

Entropy (instability) increases with dielectric thickness (voltage)

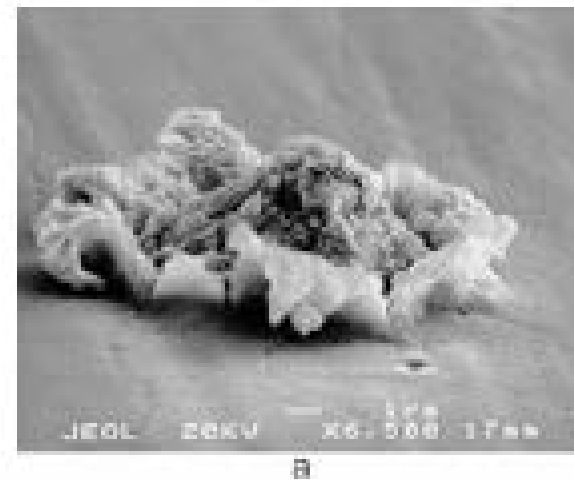
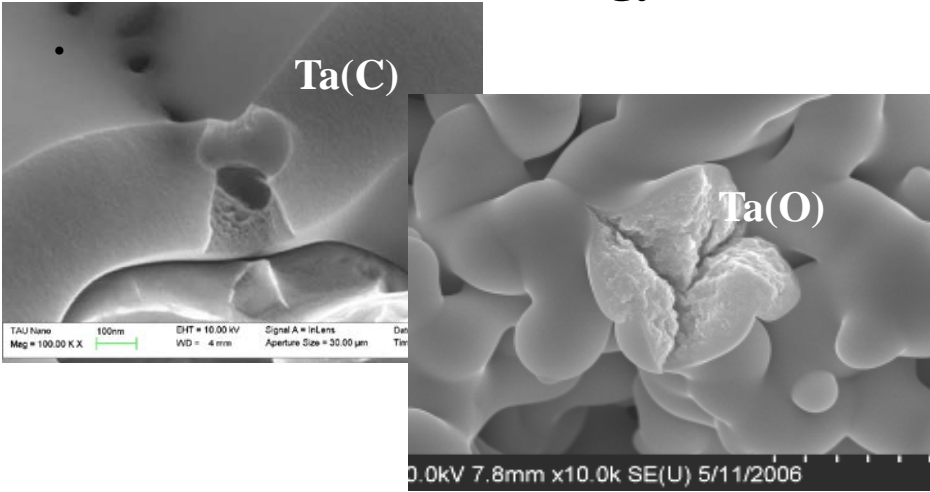


Fig. 1.14 SEM image of the anodic oxide film

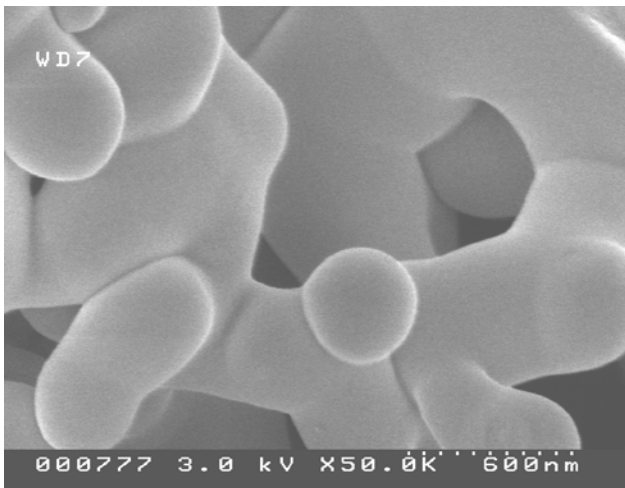


F-Tech and SBDS

Conventional Technology

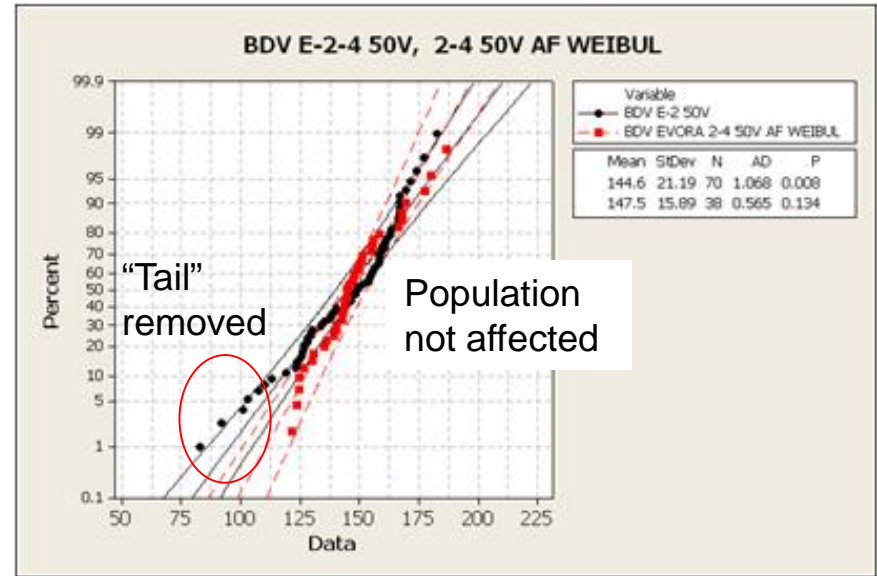


F-Tech



(verified on every production lot)

100% Simulated Breakdown Screening (SBDS)



Crystallization will happen, but this can occur in 100 hours or 100 years

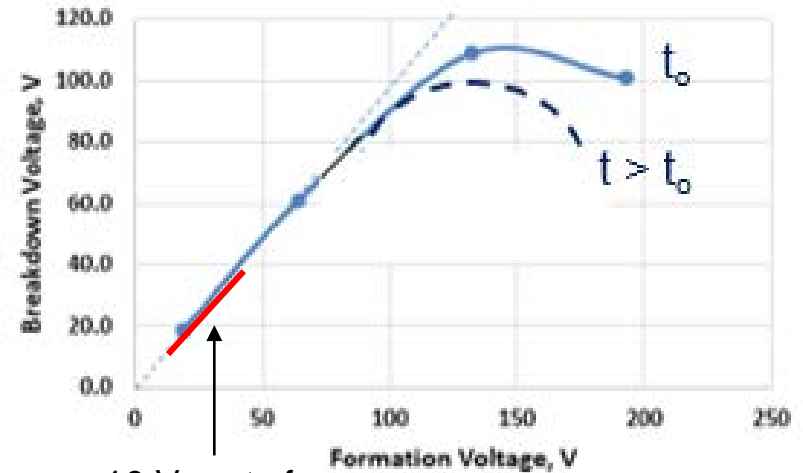
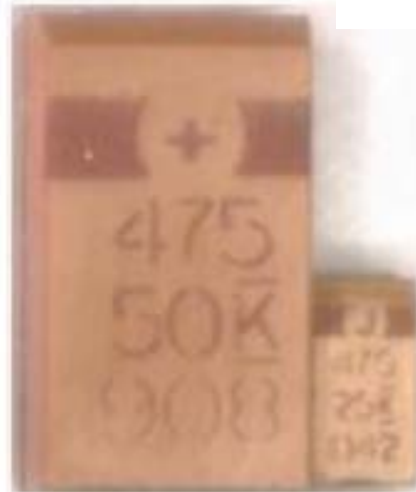


De-rating

$$\frac{t_1}{t_2} = \left(\frac{V_2}{V_1}\right)^n \exp\left[\frac{E_a}{kT}\left(\frac{1}{T_1} - \frac{1}{T_2}\right)\right]$$

$$V_{50}/V \approx 10$$

Fig. 3.19 MnO₂ tantalum capacitors: D-case 4.7 μF, 50 V (left), and A-case 4.7 μF, 25 V (right)



10 V parts for
3.3 V application



Hi-Rel and COTS vs. Commercial (Automotive)

	MIL-PRF-55365 T-Level	MIL-PRF-55365	COTS	Commercial
KEMET Series	409/419/429/492	409/419/429/492	497*	490/491
DPA	X			
100% X-ray	X			
Group C Testing	X			
+3 Std Dev Screening	X			
Established Reliability	B, C, D	B, C, D	B, C	
Surge Current	X	X	X	
Mil Maintenance	X	X		
F-TECH			optional	
SBDS			optional	

Made
in
USA

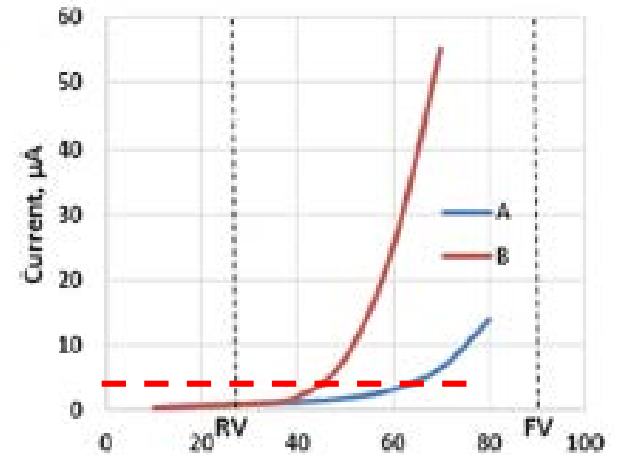
Automotive: moisture resistance



Make “New Space” with reliable parts



Fig. 3.25 I(V) characteristics of the D-case 16 μ F - 25 V MnO₂ tantalum capacitors



Powder cost = price * weight P

$$P = \text{const} * CV * \frac{V_f / V}{CV_f / g}$$

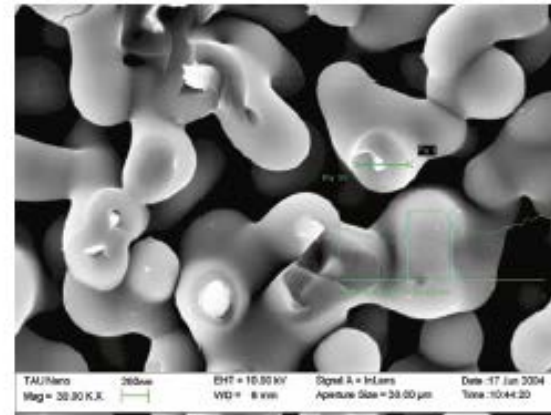


Fig. 3.3 Breakage of the tantalum anode sintered with 50,000 μ C/g tantalum powder and formed to 75 V



Anomalous Charge Current (ACC)

Bake out 125 C for 24 h plus two Pb-free reflow

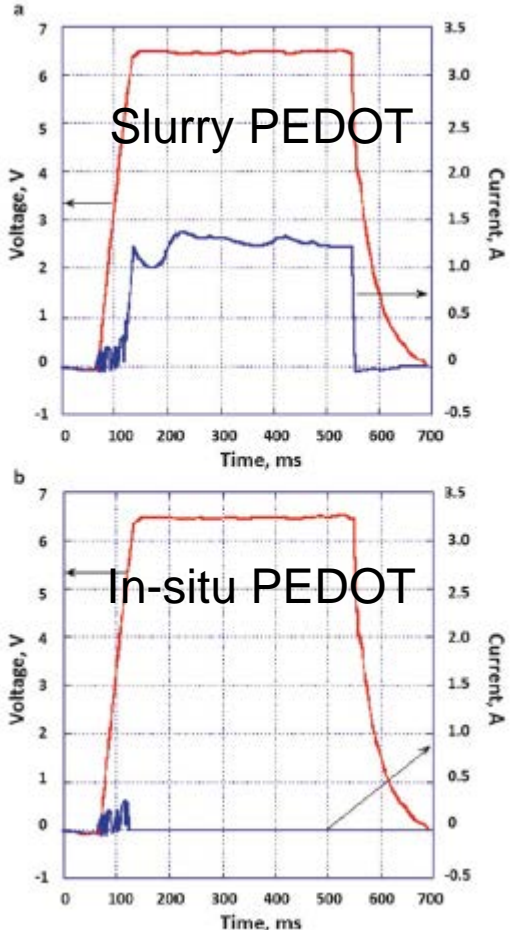
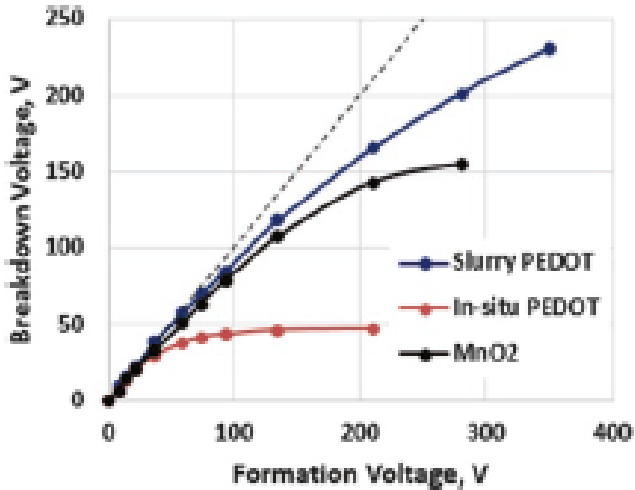


Fig. 3.34 BDV vs. formation voltage in tantalum capacitors with F-Tech anode and either slurry PEDOT, in situ PEDOT, or MnO₂ cathode



JES 2014 - record number of citations

Fig. 3.54 I(t) response to one pulse, V(t), applied at -200 °C to a W-case 470 μF - 6.3 V hybrid (a) and pure in situ (b) polymer tantalum capacitors

Effects of Moisture

Negative

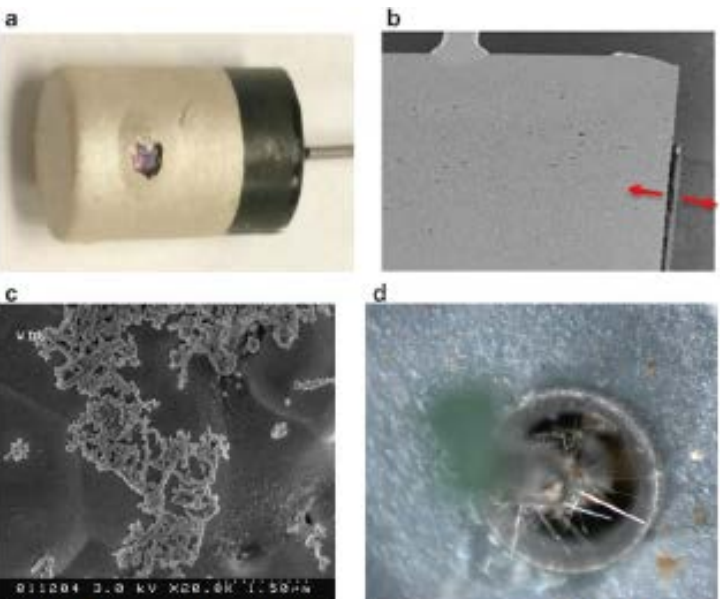
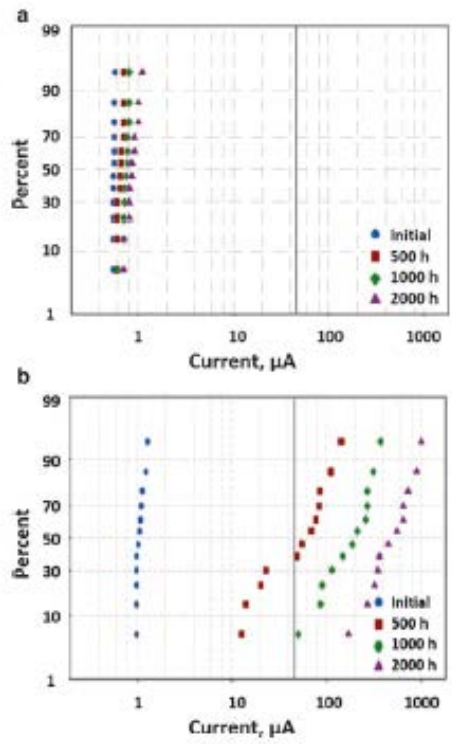


Fig. 3.49 Moisture-related failures in PHS tantalum capacitors: popcorn effect (a), delamination of the external carbon and silver layers (b), silver migration (c), and tin whiskers (d)

Positive

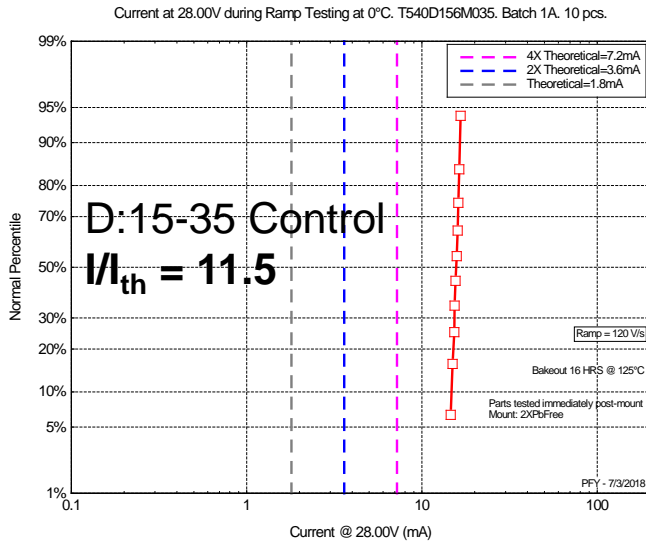
Fig. 3.40 DCL during life test at rated voltage and 85 °C in B-case 75 μ F – 75 V humid (a) and dry (b) PHS tantalum capacitors



ACC Control vs. New with Improved Anode

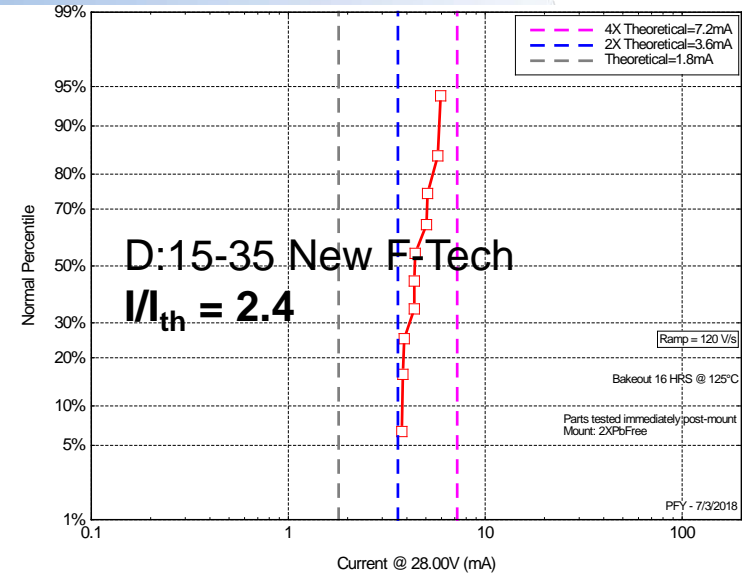
$dV/dt = 120 \text{ V/s}$, $V = 0.8 \text{ RV}$, $T = 0^\circ \text{ C}$

$$I_{th} = C * dV/dt$$

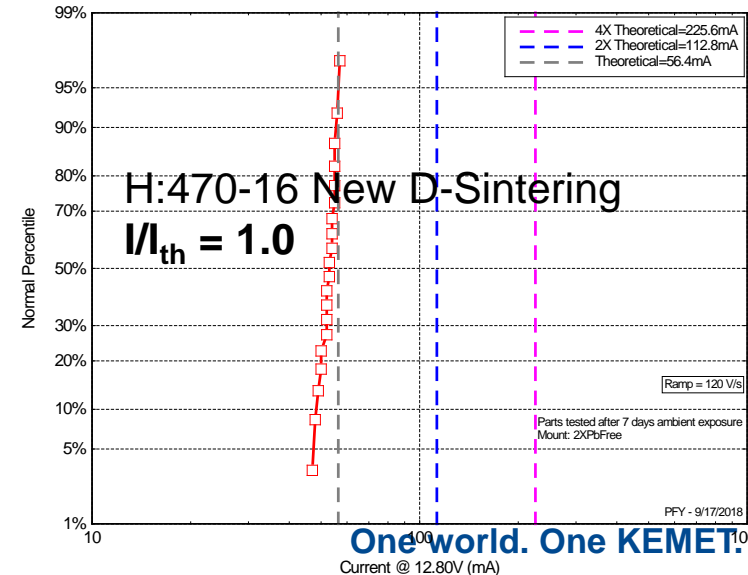


From high to low/no ACC with top reliability due to the anode improvement

Current at 28.00V during Ramp Testing at 0°C. T540D156M035. Batch 10A. 10 pcs.



Current at 12.80V during Ramp Testing at 0°C. T523H477M016. Batch ED17Z4H1B. 20 pcs.



Evolution of Tantalum Capacitors

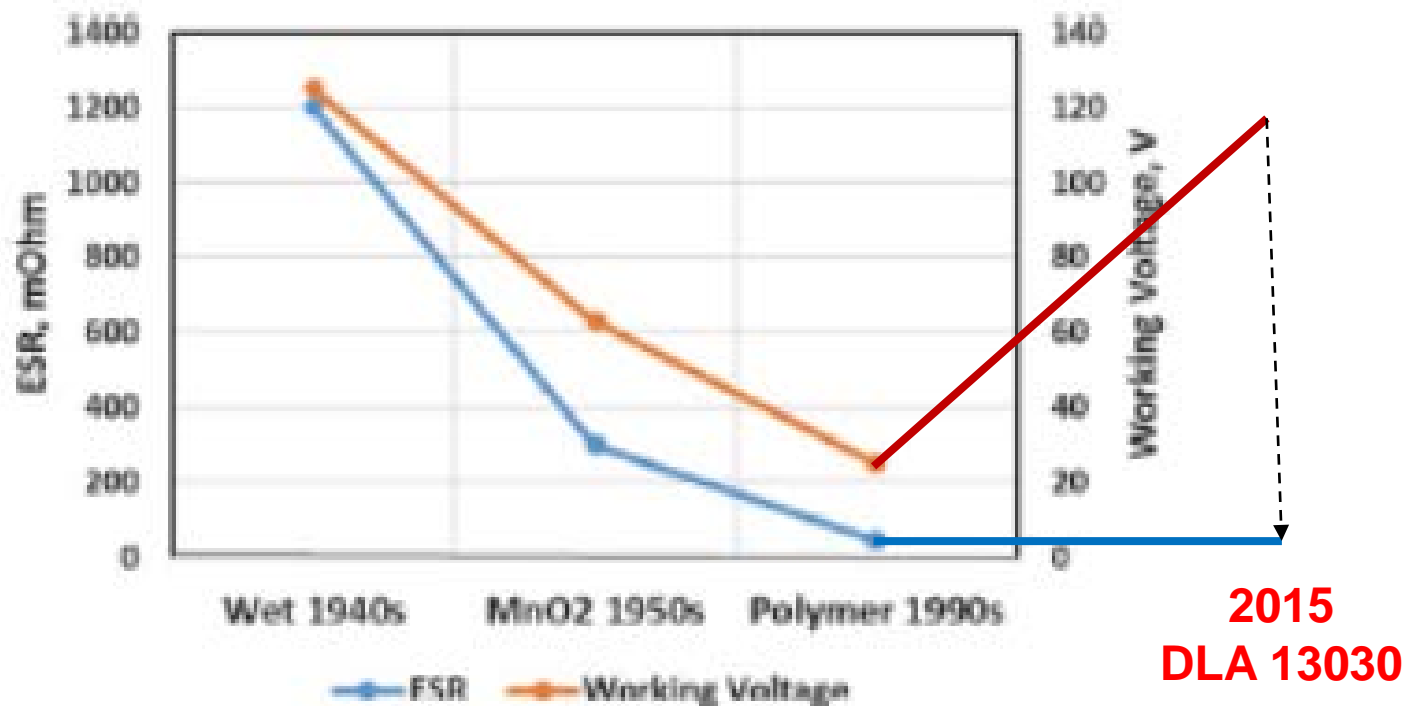


Fig. 4 ESR and maximum working voltage in different types of tantalum capacitors

PHS: on par with Wets in Voltage,
10x-100x lower ESR, MIL Qual



Conclusions

- Entropy (thermodynamic instability) of amorphous Ta₂O₅ increases with voltage (thickness of the dielectric). Advanced technologies like F-Tech/SBDS stabilize the dielectric, screen hidden defects, and provide high reliability to higher voltage parts.
- 50% de-rating of Ta caps cuts efficiency 90%, approaching efficiency of ceramic caps. 20% de-rating of Ta caps with advanced technologies provides high efficiency and high reliability plus non-ignition failure mode in Polymer caps.
- Only parts with established reliability (Hi-Rel and special COTS) are recommended for the space application. Commercial (automotive) parts can vary materials and processes, increasing risk of failure in space application.
- Low/no ACC and high reliability in higher voltage Polymer parts can be achieved by improvements in all the layers of the basic capacitor structure (not just Poly) instead of de-rating 50+% and losing 90+% efficiency.

